

# X-5000

## Mobile XRF Analyzer with Silicon Drift Detector Technology



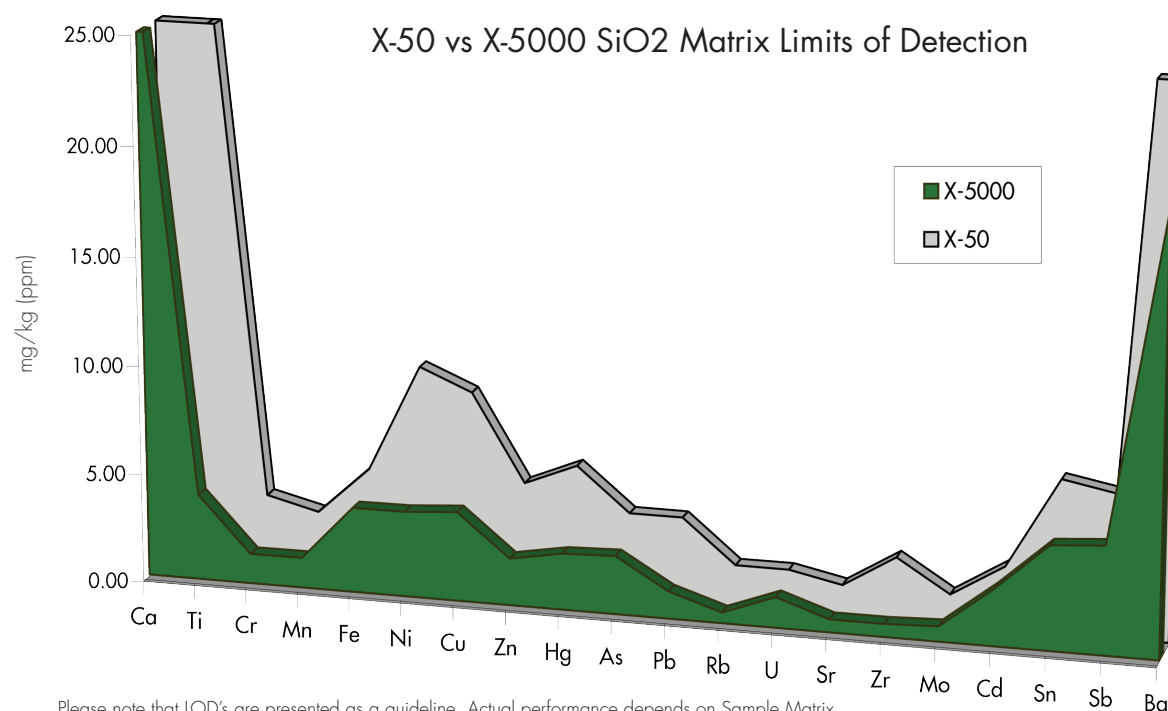
### Power and Performance in a Portable Package

For those who demand benchtop analytical power with easy portability, Innov-X offers the field-hardened X-5000 for on-site analysis in virtually any environment.

The X-5000 offers a higher level of power and performance not possible in smaller handheld XRF analyzers by utilizing the latest in detector technology – an innovative, large area Silicon Drift Detector (SDD), used and tested extensively in high end, laboratory based instrumentation.

In comparison to a traditional Si PiN Diode detector, the SDD provides:

- > 10x improvement in signal to background ratio
- > Marked resolution improvement, over 30eV
- > The capacity to handle 10x more counts
- > Greater than 3x improvement in reading speed
- > Light element (Al, Si, P, S) analysis in air



Please note that LOD's are presented as a guideline. Actual performance depends on Sample Matrix. Contact Innov-X Systems to discuss your analytical needs.

Limits of detection (LOD's) are based on 120 second test time per hardware condition (3 conditions), homogeneous loose powder. LOD's are based on 99.7% (3 Sigma) confidence levels. LOD's for Soil and Low-density Geological matrices depend on:

- > Sample preparation
- > Sample matrix
- > Interfering elements
- > Testing time
- > Statistical confidence level
- > Test conditions; Tube anode, voltage, current, primary beam filter (if applied)

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